Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"20020032037"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/06/02 16:19
L2	5	"6332143"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/06/02 16:56
L3	4	"6498921"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/06/02 16:25
L4	39	"natural language" and questionnaire and network and database and (classification or classify or cluster or clustering)and engine	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/02 17:12
L5	12	4 and @ad<"20000315"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/02 17:12
L6	39	"natural language" and questionnaire and network and (classification or classify or cluster or clustering)and engine	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/02 17:12
Ĺ7	59	"natural language" and questionnaire and network and (classification or classify or cluster or clustering)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/02 17:12
L8	20	7 and @ad<"20000315"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/02 17:12

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Publications/Services Standards Conferences Careers/Jobs

Welcome



United States Patent and Trademark Office FAQ Terms IEEE Peer Review **Quick Links** Welcome to IEEE Xplore® Your search matched 0 of 1041798 documents. ()- Home A maximum of 500 results are displayed, 50 to a page, sorted by Relevance)- What Can Descending order. | Access? ()- Log-out **Refine This Search:** You may refine your search by editing the current search expression or enteri **Tables of Contents** new one in the text box. O- Journals statement and (natural language) and (text classification Search & Magazines Check to search within this result set O- Conference **Proceedings Results Key:** Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author O- Basic **Results:** O- Advanced No documents matched your query. Member Services O Join IEEE)- Establish IEEE **Web Account** O- Access the **IEEE Member Digital Library**

Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright @ 2004 IEEE - All rights reserved



US Patent & Trademark Office

Subscribe (Full Service) Register (Limited Service, Free) Login

Search: © The ACM Digital Library O The Guide

+statement +and +(natural +langauage) +and +(text +classif

HEXTER:

Nothing Found

Your search for +statement +and +(natural +langauage) +and +(text +classification) +and +learning +and +rule +and +readout did not return any results.

You may want to try an Advanced Search for additional options.

Please review the Quick Tips below or for more information see the Search Tips.

Quick Tips

• Enter your search terms in lower case with a space between the terms.

sales offices

You can also enter a full question or concept in plain language.

Where are the sales offices?

• Capitalize proper nouns to search for specific people, places, or products.

John Colter, Netscape Navigator

• Enclose a phrase in double quotes to search for that exact phrase.

"museum of natural history" "museum of modern art"

• Narrow your searches by using a + if a search term must appear on a page.

museum +art

• Exclude pages by using a - if a search term must not appear on a page.

museum -Paris

Combine these techniques to create a specific search query. The better your description of the information you want, the more relevant your results will be.

museum +"natural history" dinosaur -Chicago

The ACM Portal is published by the Association for Computing Machinery, Copyright © 2004 ACM, Inc. Terms of Usage Privacy Policy Code of Ethics Contact Us

Useful downloads: Adobe Acrobat Q QuickTime Windows Media Player

O- By Author

Member Services

- Join IEEE

O- Access the

Print Format

- Establish IEEE **Web Account**

IEEE Member Digital Library

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership	Publications/Services	Standards	Conferences
JEE	E Xplore) ®	Inited States Pa

Welcome **United States Patent and Trademark Office**

Careers/Jobs



Help	FAQ	Terms	IEEE Peer Review	Quick Links	Ø	» Se.		
66	Home What (I Acce:	ss?	Your searc			a page, sorted by Relevance		
Tables	Log-ou of Con	tents	You may r	nis Search: refine your search by n the text box.	editing the currer	nt search expression or enteri		
O- Journals (natur				nguage) and (text classit	fication)	Search.		
	Conference Proceedings							
O-Standards Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard								
Search	1							

1 Text classification and keyword extraction by learning decision tree O- Basic Sakakibara, Y.; Misue, K.; Koshiba, T.; O- Advanced

Artificial Intelligence for Applications, 1993. Proceedings., Ninth Conference o 5 March 1993

Pages:466

[Abstract] [PDF Full-Text (72 KB)] **IEEE CNF**

2 A hybrid architecture for text classification

Register, M.S.; Kannan, N.;

Tools with Artificial Intelligence, 1992. TAI '92, Proceedings., Fourth Internati Conference on , 10-13 Nov. 1992

Pages: 286 - 292

[Abstract] [PDF Full-Text (456 KB)] **IEEE CNF**

3 Text classification in fragmented sublanguage domains

Frail, R.P.; Freedman, R.S.;

Artificial Intelligence for Applications, 1991. Proceedings., Seventh IEEE Confe on , Volume: i , 24-28 Feb. 1991

Pages:33 - 36

[Abstract] [PDF Full-Text (344 KB)] **IEEE CNF**

4 Towards classifying full-text using recurrent neural networks

Farkas, J.;

Electrical and Computer Engineering, 1995. Canadian Conference on , Volume 1, 5-8 Sept. 1995

Pages:511 - 514 vol.1

[PDF Full-Text (436 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top